
Symposium on

ADVANCES IN
TECHNIQUES IN ELECTRON
METALLOGRAPHY



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SYMPOSIUM ON ADVANCES IN TECHNIQUES IN ELECTRON METALLOGRAPHY

Sponsored by
SUBCOMMITTEE XI ON ELECTRON MICROSTRUCTURE OF METALS
OF
ASTM COMMITTEE E-4 ON ELECTRON METALLOGRAPHY

Held at
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FOREWORD

The papers included in this publication were presented at the Sixty-fifth Annual Meeting of the American Society for Testing and Materials in New York, N. Y., at a Technical Session on June 26, 1962. This session was sponsored by Subcommittee XI on Electron Microstructure of Metals of ASTM Committee E-4 on Metallography.

One paper presented at this session is not included here: "Direct Observations on an Age Hardening Cu - 3 per cent Co Alloy" by V. A. Phillips; it has been published elsewhere.

In addition to these papers, several others have been included in this publication because of their relevancy to the subcommittee's activities. These are the papers by L. Sturkey, R. C. Glenn and J. C. Raley, and W. A. Fragetta and J. R. Mihalisin, as well as the discussion by E. T. Stephenson of the paper by Mr. Beu.

J. R. Mihalisin, of The International Nickel Co., Inc., acted as chairman of the subcommittee meetings, and W. R. Lasko, of United Aircraft Corp., as secretary. P. K. Koh, of the Bethlehem Steel Co., presided over the Technical Session.

NOTE.—The Society is not responsible, as a body, for the statements
and opinions advanced in this publication.

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